

Notice of References Cited

Application/Control No.

10/044,095

Applicant(s)/Patent Under
Reexamination
YUEN, SILTEX PETER

Examiner

Conrad J. DeWitte

Art Unit

2673

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,628,074 B1	09-2003	Saito et al.	313/582
	B	US-6,614,423 B1	09-2003	Wong et al.	345/173
	C	US-6,608,664 B1	08-2003	Hasegawa, Fumio	349/160
	D	US-6,590,337 B1	07-2003	Nishikawa et al.	313/509
	E	US-6,304,251 B1	10-2001	Ito et al.	345/173
	F	US-6,137,555 A	10-2000	Tamura et al.	349/95
	G	US-6,089,646 A	07-2000	Xu et al.	296/146.15
	H	US-6,088,024 A	07-2000	Yamagata, Hideto	345/173
	I	US-6,002,389 A	12-1999	Kasser, Bernard	345/173
	J	US-5,990,874 A	11-1999	Tsumura et al.	345/173
	K	US-5,729,250 A	03-1998	Bishop et al.	345/175
	L	US-4,812,830 A	03-1989	Doering, Roger W.	345/175
	M	US-2002/0063695 A1	05-2002	Canova, Francis James JR.	345/173

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.